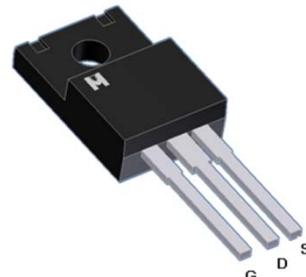
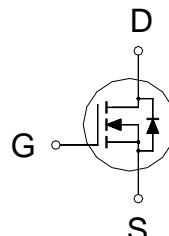


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV <sub>DSS</sub>	900V
R <sub>DSON</sub> (MAX.)	4Ω
I <sub>D</sub>	3.5A



UIS, 100% Tested

Pb-Free Lead Plating & Halogen Free



**ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25 °C Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V <sub>GS</sub>	±30	V
Continuous Drain Current	T <sub>C</sub> = 25 °C	I <sub>D</sub>	3.5	A
	T <sub>C</sub> = 100 °C		2.2	
Pulsed Drain Current <sup>1</sup>		I <sub>DM</sub>	14	
Avalanche Current		I <sub>AS</sub>	3	
Avalanche Energy	L = 3mH, I <sub>D</sub> =3A, R <sub>G</sub> =25Ω	E <sub>AS</sub>	13.5	mJ
Repetitive Avalanche Energy <sup>2</sup>	L = 0.5mH	E <sub>AR</sub>	2.25	
Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	32	W
	T <sub>C</sub> = 100 °C		13	
Operating Junction & Storage Temperature Range		T <sub>j</sub> , T <sub>stg</sub>	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R <sub>θJC</sub>	3.8	3.8	°C / W
Junction-to-Ambient	R <sub>θJA</sub>		80	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

ELECTRICAL CHARACTERISTICS ( $T_c = 25^\circ\text{C}$ , Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	900			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	2	3	4	
Gate-Body Leakage	$I_{\text{GSS}}$	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 30\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 900\text{V}, V_{\text{GS}} = 0\text{V}$			10	$\mu\text{A}$
		$V_{\text{DS}} = 720\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			25	
Drain-Source On-State Resistance <sup>1</sup>	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 1.8\text{A}$		3.2	4	$\Omega$
Forward Transconductance <sup>1</sup>	$g_{\text{fs}}$	$V_{\text{DS}} = 25\text{V}, I_D = 1.8\text{A}$		3.6		S
DYNAMIC						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		605		pF
Output Capacitance	$C_{\text{oss}}$			64		
Reverse Transfer Capacitance	$C_{\text{rss}}$			3.3		
Total Gate Charge <sup>1,2</sup>	$Q_g$	$V_{\text{DS}} = 450\text{V}, V_{\text{GS}} = 15\text{V}, I_D = 1.8\text{A}$		10.4		nC
Gate-Source Charge <sup>1,2</sup>	$Q_{\text{gs}}$			2.6		
Gate-Drain Charge <sup>1,2</sup>	$Q_{\text{gd}}$			2.8		
Turn-On Delay Time <sup>1,2</sup>	$t_{\text{d}(\text{on})}$			10		
Rise Time <sup>1,2</sup>	$t_r$	$V_{\text{DS}} = 400\text{V}, I_D = 1\text{A}, V_{\text{GS}} = 15\text{V}, R_{\text{GS}} = 10\Omega$		9		nS
Turn-Off Delay Time <sup>1,2</sup>	$t_{\text{d}(\text{off})}$			15		
Fall Time <sup>1,2</sup>	$t_f$			10		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_c = 25^\circ\text{C}$ )						
Continuous Current	$I_S$				3.5	A
Pulsed Current <sup>3</sup>	$I_{\text{SM}}$				14	
Forward Voltage <sup>1</sup>	$V_{\text{SD}}$	$I_F = I_S, V_{\text{GS}} = 0\text{V}$			1.5	V
Reverse Recovery Time	$t_{\text{rr}}$	$I_F = I_S, dI_F/dt = 100\text{A}/\mu\text{s}$		0.5		$\mu\text{s}$
Reverse Recovery Charge	$Q_{\text{rr}}$			2		nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

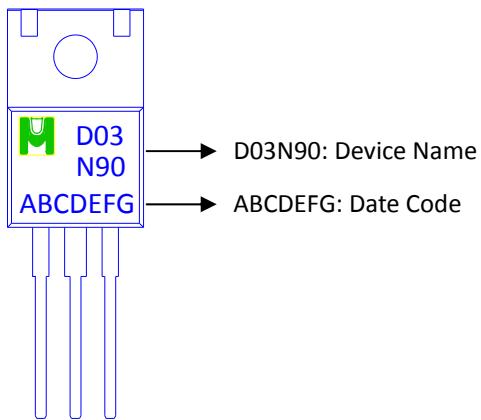
<sup>2</sup>Independent of operating temperature.

<sup>3</sup>Pulse width limited by maximum junction temperature.

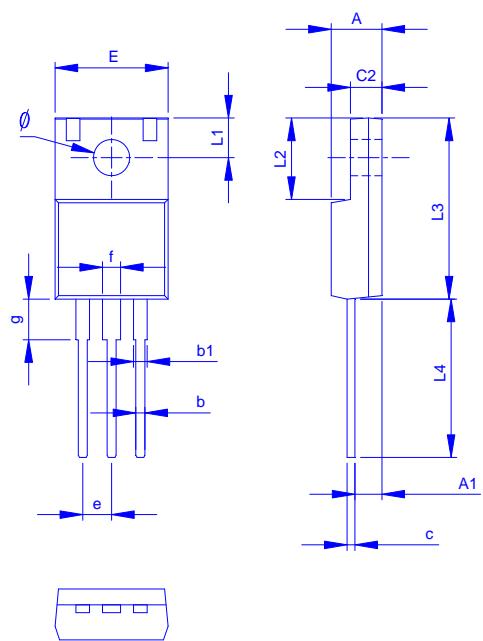


Ordering & Marking Information:

Device Name: EMD03N90F for TO-220F



Outline Drawing



Dimension in mm

Dimension	A	A1	b	b1	c	c2	E	L1	L2	L3	L4	ø	e	f	g
Min.	4.20	1.95	0.50	0.90	0.45	2.34	9.70	2.70	6.48	14.80	12.68	3.00	2.35	1.18	3.13
Max.	4.90	2.96	1.05	1.50	0.80	3.20	10.66	3.80	7.50	16.30	14.50	3.50	2.75	1.90	4.00

### TYPICAL CHARACTERISTICS

